



# **Neural Interfaces**

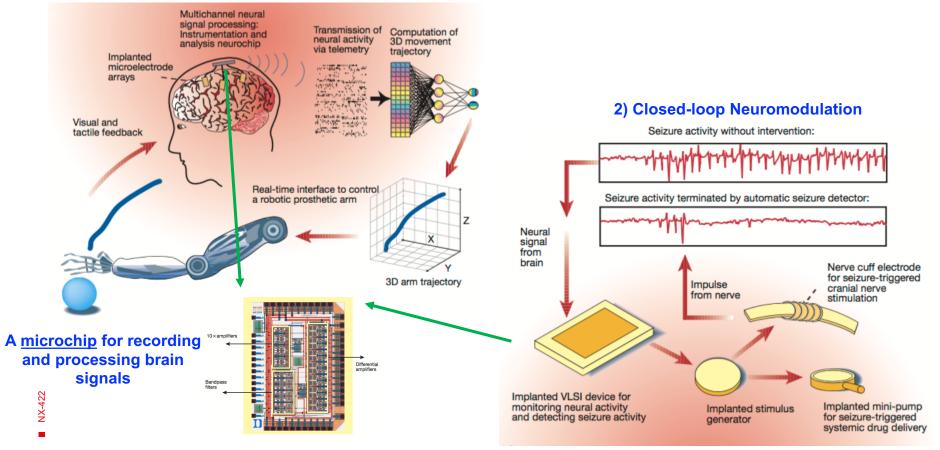
**Neural Amplifiers** 

Mahsa Shoaran IEM and Neuro-X Institutes

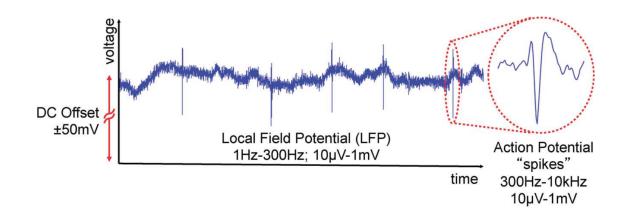


# **Recap: Two Types of Neural Interfaces**

1) Brain-Machine Interface



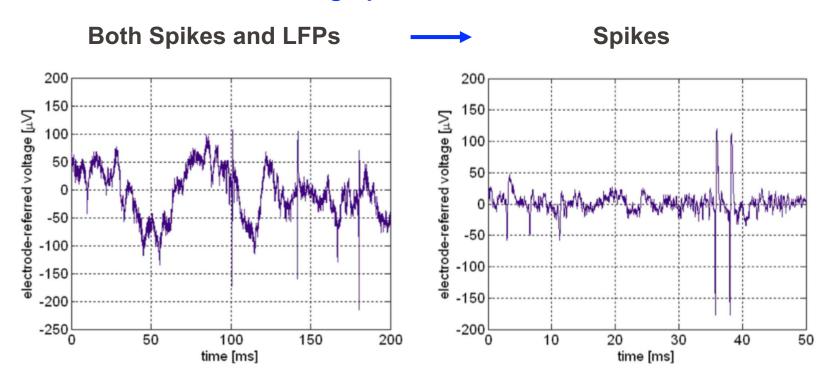
- < 300 Hz : Local Field Potentials (LFP)</p>
- 300 10kHz : Single-Unit Activity (AP or "spikes")
- Local Field Potential (LFP) electrical activity of all cells averaged over some spatial neighborhood
- High-pass filtering gives spikes





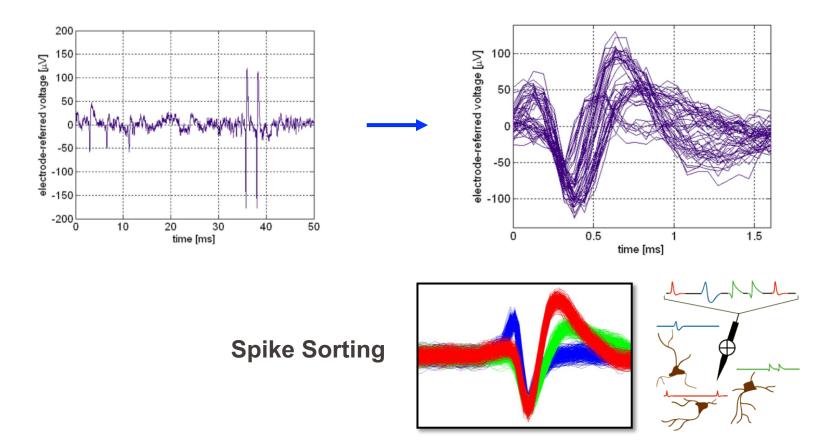
# **Spike/LFP Recording**

#### **High-pass filter at 300Hz**



# **Spike Sorting**

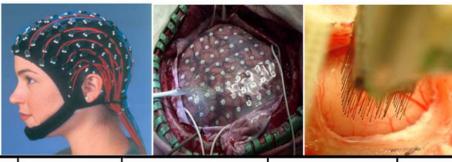




NX-422

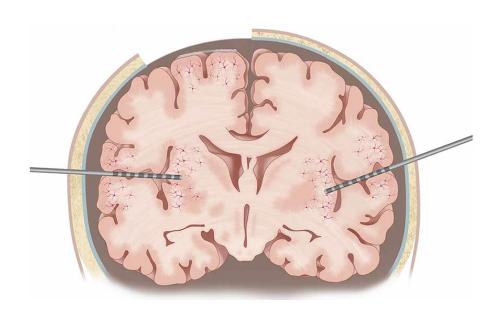


# **Comparison: EEG, ECoG, LFP, and AP**



	EEG	ECoG	LFP	AP	
Bandwidth	0.5-50Hz	1-500Hz	1-500Hz	250-10kHz	
Amplitude	1-50µV	1-500µV	10μ-1mV	10μ-1mV	
Spacing	3cm	0.2-10mm	0.1-1mm	0.1-1mm	
Invasive	No	Craniotomy, no neural damage	Craniotomy, neural damage	Craniotomy, neural damage	
Area Coverage	Whole Brain	~ cm² , whole brain	~ mm²	~ mm²	
Stability	Decades	Decades	Years	Months	

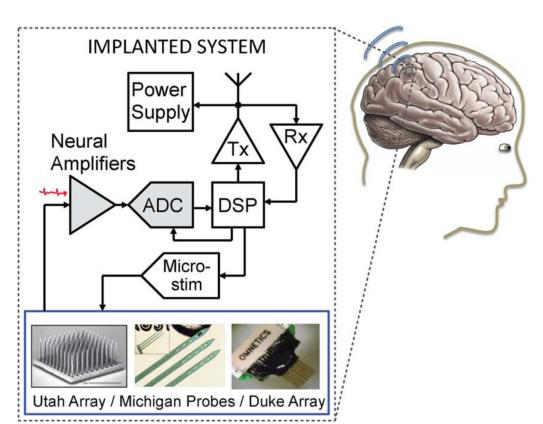
# **Stereo EEG (sEEG)**







# **Circuit Block Diagram of a Neural Interface**

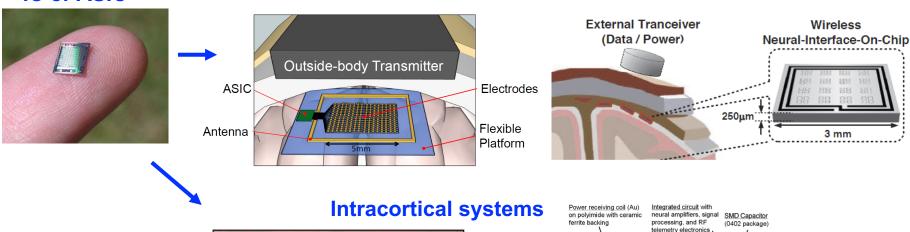


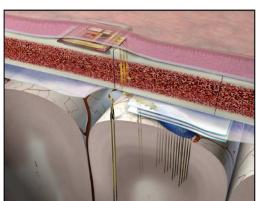
# **Cortical and Intracortical Systems**

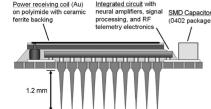
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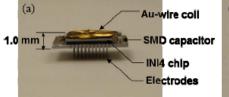


#### **Cortical or ECoG-based systems**









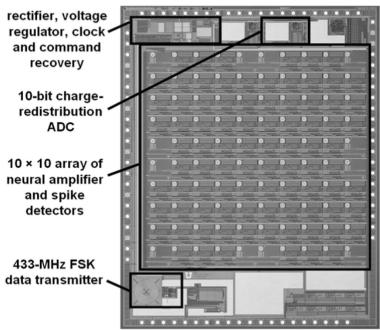


### **EPFL**

# **Neural Recording IC**

Microchips include amplification, filtering, digitization, compression, processing: feature extraction/spike detection/classification, wireless power and data telemetry, bias generation, stimulation, ...

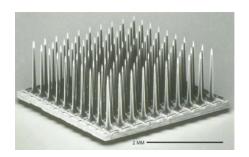
Power and area are highly limited

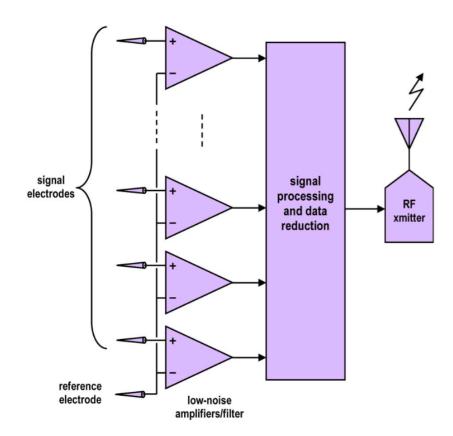


Die photo of 4.7 mm x 5.9 mm chip



# **Low-Noise Neural Amplifier**





### **EPFL**

# **Design Requirements for Neural Amplifier**

- 1. Sufficiently low input-referred noise to resolve spikes as small as 10 μV in amplitude
- 2. Sufficient dynamic range to record spikes or LFPs as large as 1–2 mV in amplitude
- 3. Much higher input impedance than the electrode-tissue interface
- 4. Amplify signals in the frequency bands of interest (roughly 300 Hz–10 kHz for spikes and 1–300 Hz for local field potentials)
- 5. Block DC offsets present at the electrode-tissue interface to prevent saturation of the amplifier

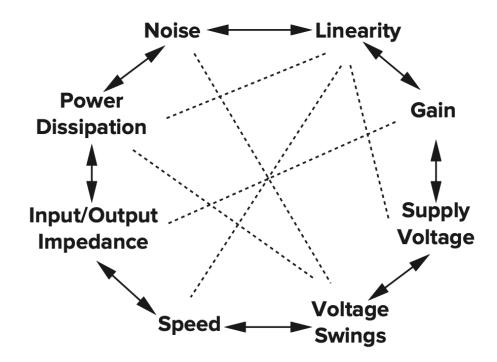
### **EPFL**

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- 5. Block DC offsets present at the electrode-tissue interface to prevent saturation of the amplifier
- 6. Consume little silicon area and use few or no off-chip components to minimize size
- 7. High common-mode rejection ratio to minimize interference from 50/60 Hz power line noise, and a high power-supply rejection ratio if power supply noise is significant (e.g., from ac inductive power links);
- 8. Consume low power to limit the chronic heating of surrounding tissue to less than 1°C.

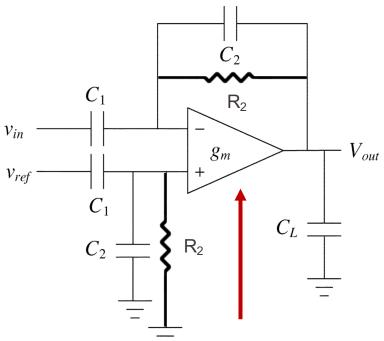
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# **Design Trade-offs**

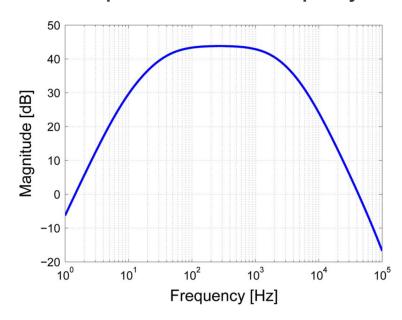




## **Neural Amplifier: Capacitive Feedback Architecture**



#### **Amplifier Gain versus Frequency**



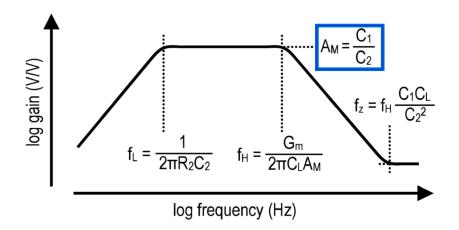
**OTA**:

**Operational Transconductance Amplifier** 

## **Neural Amplifier: Transfer Function**

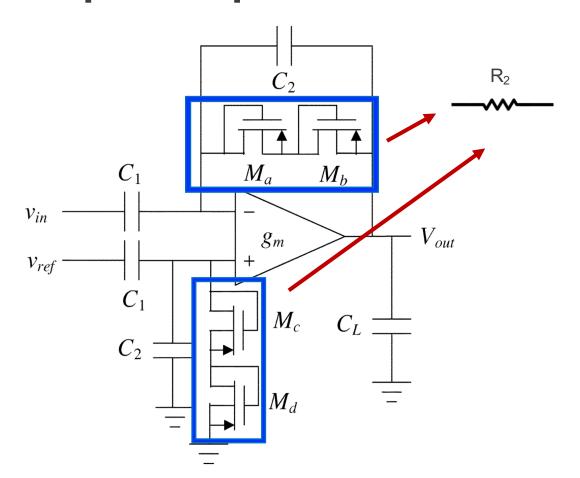
$$\frac{v_{\text{out}}}{v_{\text{in+}} - v_{\text{in-}}} = \frac{C_1}{C_2} \cdot \frac{1 - sC_2/G_m}{\left(\frac{1}{sR_2C_2} + 1\right) \left(s\frac{C_LC_1}{G_mC_2} + 1\right)}$$

$$= A_M \frac{1 - s/(2\pi f_z)}{\left(\frac{2\pi f_L}{s} + 1\right) \left(\frac{s}{2\pi f_H} + 1\right)}.$$



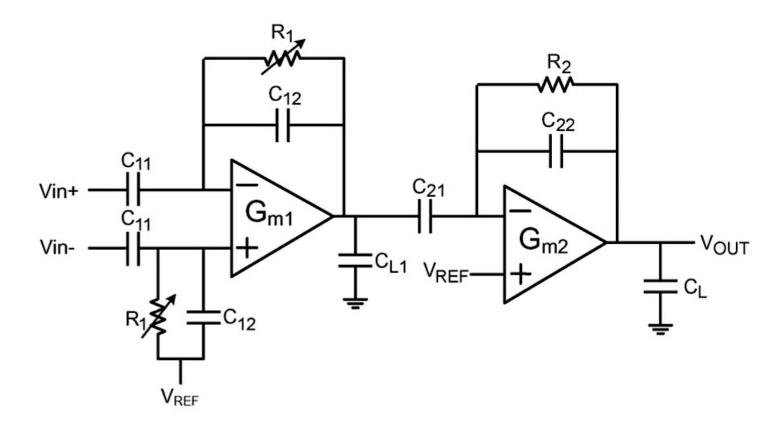


# **Neural Amplifier: Capacitive Feedback Architecture**





# **Neural Amplifier: Multi-Stage, Higher Gain**





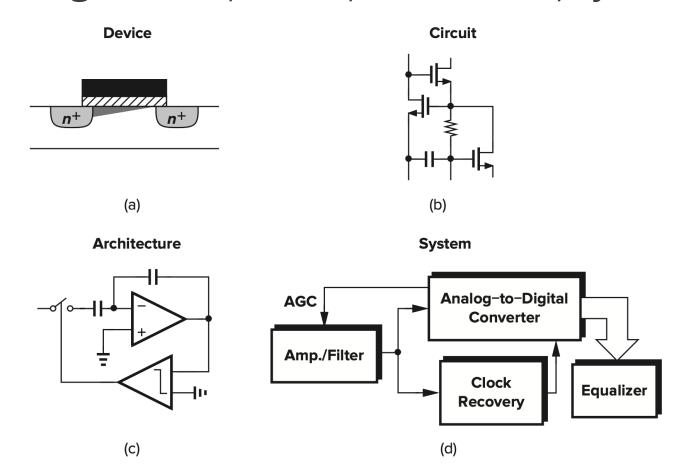
## **Neural Implants: Power, Area, Noise, ...**

A typical performance and comparison table

	JSSC ,08 [3]	[4] JSSC '07	[6] BioCAS '07	[7] ISSCC '10	[24] VLSI '11	This Work
Power (µW)	15	42.2	7.56	0.64	43	5.04
IRNoise (μV), Spike	7.0	5.1	3.06	14	2.2	4.9
Spike Bandwidth	5kHz	5kHz	5.3kHz	6.2kHz	10kHz	10kHz
NEF	4.6	9.8	2.67	6.5	5	5.99
NEF <sup>2</sup> •V <sub>DD</sub>	63.48	316.9	20	33.8	30	17.96
IRNoise (μV), LFP	-	-	1.66*	-	14	4.3
LFP Bandwidth	-	-	300Hz*	-	100Hz	300Hz
CMRR (dB)	-	-	66	59	-	75
PSRR (dB)	-	-	75	71	-	64
V <sub>DD</sub> (V)	3	3.3	2.8	0.8	1.2	0.5
Area (mm²)	0.04	0.16	0.16	0.4**	0.2**	0.013
Technology	0.35µm	0.5µm	0.5µm	0.13µm	0.13µm	65nm
Blocks included in comparison	LNA, BPF	LNA, BPF	LNA, BPF	LNA, BPF	LNA, BPF, ADC	LNA, BPF, ADC

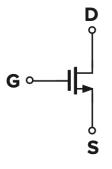


## IC Design: Device, Circuit, Architecture, System



### **Transistor?**

#### **NMOS**



$$I_D pprox rac{1}{2} \mu_n C_{ox} rac{W}{L} (V_{GS} - V_{TH})^2$$

### **EPFL** NMOS Transistor

- An n-type MOS (NMOS) device on a p-type substrate
  - a heavily-doped polysilicon (conductor) operating as the gate
  - a thin layer of silicon dioxide (SiO<sub>2</sub>) **insulating** the gate from the substrate
  - two heavily-doped n regions: source and drain terminals

